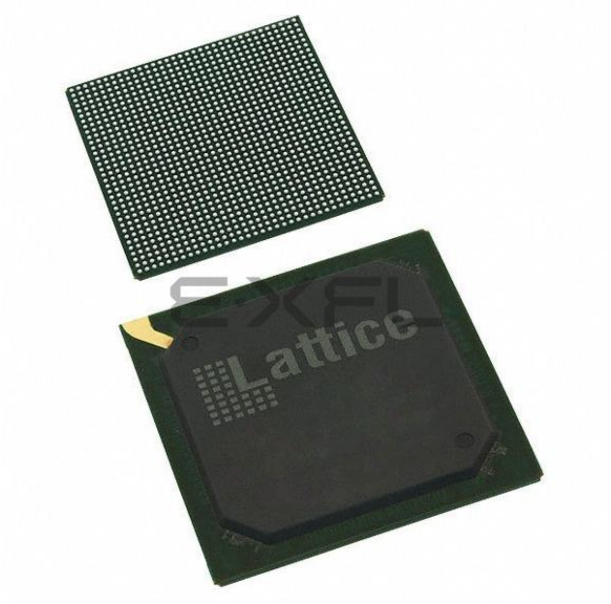

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Details	
Product Status	Active
Number of LABs/CLBs	18625
Number of Logic Elements/Cells	149000
Total RAM Bits	7014400
Number of I/O	586
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1156-BBGA
Supplier Device Package	1156-FPBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe3-150ea-7fn1156i

ROM Mode

ROM mode uses the LUT logic; hence, Slices 0 through 3 can be used in ROM mode. Preloading is accomplished through the programming interface during PFU configuration.

For more information, please refer to TN1179, LatticeECP3 Memory Usage Guide.

Routing

There are many resources provided in the LatticeECP3 devices to route signals individually or as busses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments.

The LatticeECP3 family has an enhanced routing architecture that produces a compact design. The Diamond and ispLEVER design software tool suites take the output of the synthesis tool and places and routes the design.

sysCLOCK PLLs and DLLs

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The devices in the LatticeECP3 family support two to ten full-featured General Purpose PLLs.

General Purpose PLL

The architecture of the PLL is shown in Figure 2-4. A description of the PLL functionality follows.

CLKI is the reference frequency (generated either from the pin or from routing) for the PLL. CLKI feeds into the Input Clock Divider block. The CLKFB is the feedback signal (generated from CLKOP, CLKOS or from a user clock pin/logic). This signal feeds into the Feedback Divider. The Feedback Divider is used to multiply the reference frequency.

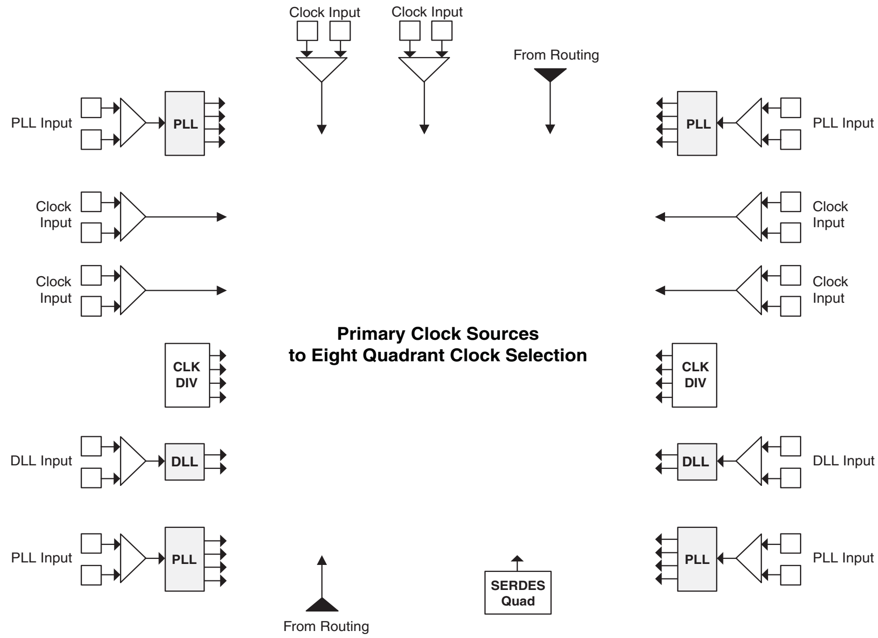
Both the input path and feedback signals enter the Phase Frequency Detect Block (PFD) which detects first for the frequency, and then the phase, of the CLKI and CLKFB are the same which then drives the Voltage Controlled Oscillator (VCO) block. In this block the difference between the input path and feedback signals is used to control the frequency and phase of the oscillator. A LOCK signal is generated by the VCO to indicate that the VCO has locked onto the input clock signal. In dynamic mode, the PLL may lose lock after a dynamic delay adjustment and not relock until the t_{LOCK} parameter has been satisfied.

The output of the VCO then enters the CLKOP divider. The CLKOP divider allows the VCO to operate at higher frequencies than the clock output (CLKOP), thereby increasing the frequency range. The Phase/Duty Cycle/Duty Trim block adjusts the phase and duty cycle of the CLKOS signal. The phase/duty cycle setting can be pre-programmed or dynamically adjusted. A secondary divider takes the CLKOP or CLKOS signal and uses it to derive lower frequency outputs (CLKOK).

The primary output from the CLKOP divider (CLKOP) along with the outputs from the secondary dividers (CLKOK and CLKOK2) and Phase/Duty select (CLKOS) are fed to the clock distribution network.

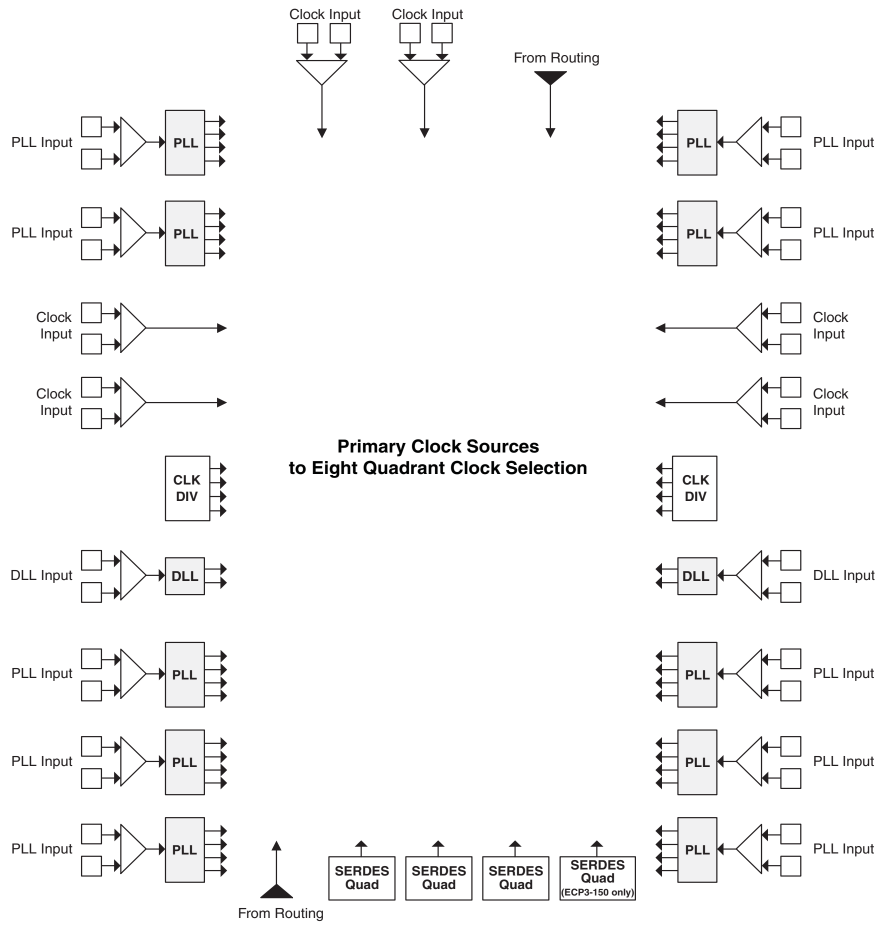
The PLL allows two methods for adjusting the phase of signal. The first is referred to as Fine Delay Adjustment. This inserts up to 16 nominal 125 ps delays to be applied to the secondary PLL output. The number of steps may be set statically or from the FPGA logic. The second method is referred to as Coarse Phase Adjustment. This allows the phase of the rising and falling edge of the secondary PLL output to be adjusted in 22.5 degree steps. The number of steps may be set statically or from the FPGA logic.

Figure 2-10. Primary Clock Sources for LatticeECP3-35



Note: Clock inputs can be configured in differential or single-ended mode.

Figure 2-11. Primary Clock Sources for LatticeECP3-70, -95, -150

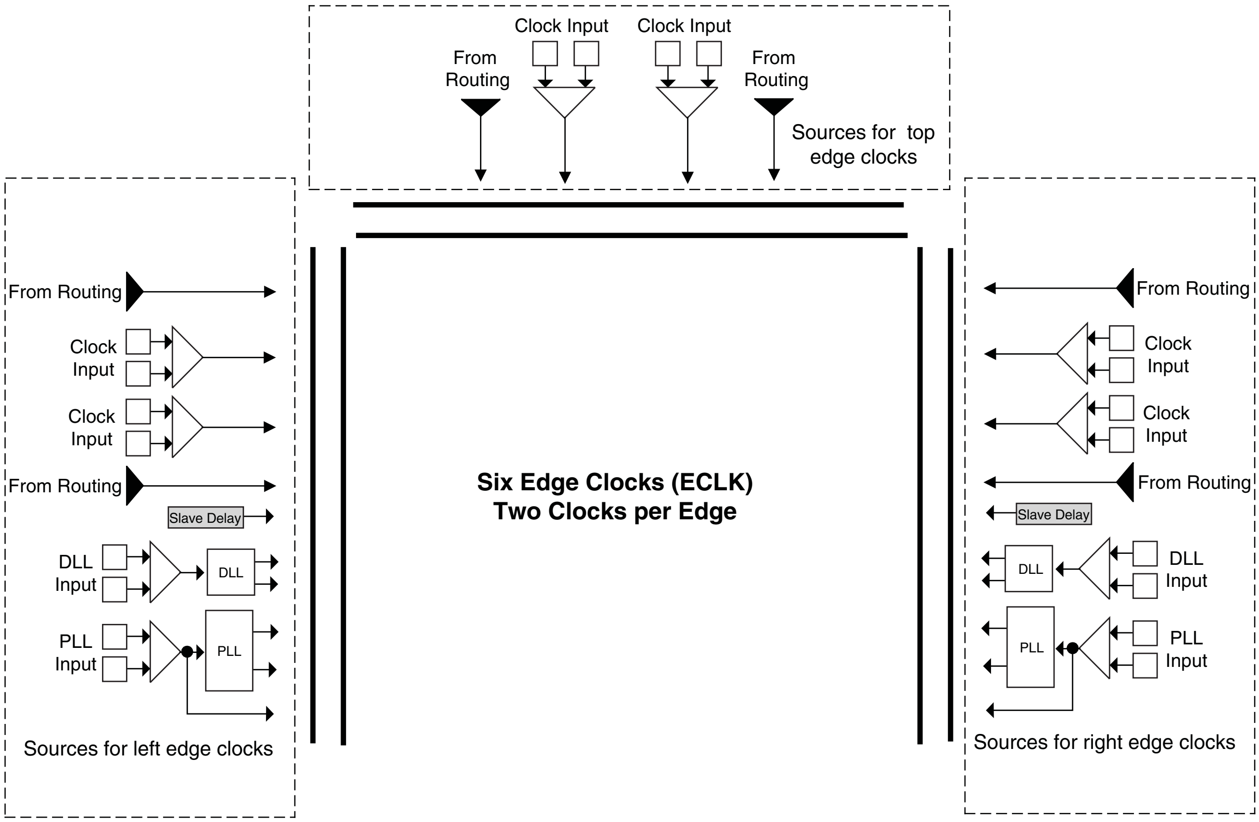


Note: Clock inputs can be configured in differential or single-ended mode.

Edge Clock Sources

Edge clock resources can be driven from a variety of sources at the same edge. Edge clock resources can be driven from adjacent edge clock PIOs, primary clock PIOs, PLLs, DLLs, Slave Delay and clock dividers as shown in Figure 2-19.

Figure 2-19. Edge Clock Sources



Notes:
1. Clock inputs can be configured in differential or single ended mode.
2. The two DLLs can also drive the two top edge clocks.
3. The top left and top right PLL can also drive the two top edge clocks.

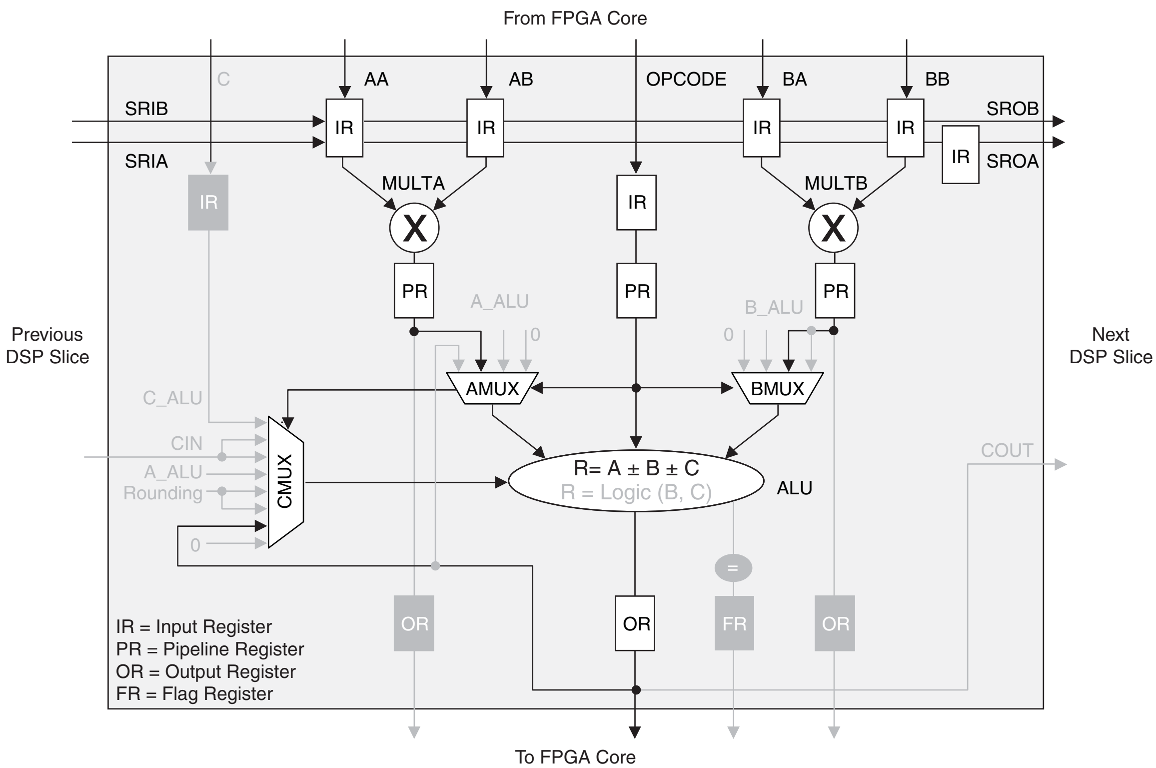
Edge Clock Routing

LatticeECP3 devices have a number of high-speed edge clocks that are intended for use with the PIOs in the implementation of high-speed interfaces. There are six edge clocks per device: two edge clocks on each of the top, left, and right edges. Different PLL and DLL outputs are routed to the two muxes on the left and right sides of the device. In addition, the CLKINDEL signal (generated from the DLL Slave Delay Line block) is routed to all the edge clock muxes on the left and right sides of the device. Figure 2-20 shows the selection muxes for these clocks.

MMAC DSP Element

The LatticeECP3 supports a MAC with two multipliers. This is called Multiply Multiply Accumulate or MMAC. In this case, the two operands, AA and AB, are multiplied and the result is added with the previous accumulated value and with the result of the multiplier operation of operands BA and BB. This accumulated value is available at the output. The user can enable the input and pipeline registers, but the output register is always enabled. The output register is used to store the accumulated value. The ALU is configured as the accumulator in the sysDSP slice. A registered overflow signal is also available. The overflow conditions are provided later in this document. Figure 2-28 shows the MMAC sysDSP element.

Figure 2-28. MMAC sysDSP Element



Input signals are fed from the sysI/O buffer to the input register block (as signal DI). If desired, the input signal can bypass the register and delay elements and be used directly as a combinatorial signal (INDD), a clock (INCK) and, in selected blocks, the input to the DQS delay block. If an input delay is desired, designers can select either a fixed delay or a dynamic delay DEL[3:0]. The delay, if selected, reduces input register hold time requirements when using a global clock.

The input block allows three modes of operation. In single data rate (SDR) the data is registered with the system clock by one of the registers in the single data rate sync register block.

In DDR mode, two registers are used to sample the data on the positive and negative edges of the modified DQS (ECLKDQSR) in the DDR Memory mode or ECLK signal when using DDR Generic mode, creating two data streams. Before entering the core, these two data streams are synchronized to the system clock to generate two data streams.

A gearbox function can be implemented in each of the input registers on the left and right sides. The gearbox function takes a double data rate signal applied to PIOA and converts it as four data streams, INA, IPA, INB and IPB. The two data streams from the first set of DDR registers are synchronized to the edge clock and then to the system clock before entering the core. Figure 2-30 provides further information on the use of the gearbox function.

The signal DDRCLKPOL controls the polarity of the clock used in the synchronization registers. It ensures adequate timing when data is transferred to the system clock domain from the ECLKDQSR (DDR Memory Interface mode) or ECLK (DDR Generic mode). The DDRLAT signal is used to ensure the data transfer from the synchronization registers to the clock transfer and gearbox registers.

The ECLKDQSR, DDRCLKPOL and DDRLAT signals are generated in the DQS Read Control Logic Block. See Figure 2-37 for an overview of the DQS read control logic.

Further discussion about using the DQS strobe in this module is discussed in the DDR Memory section of this data sheet.

Please see TN1180, LatticeECP3 High-Speed I/O Interface for more information on this topic.

Figure 2-40. SERDES/PCS Quads (LatticeECP3-150)

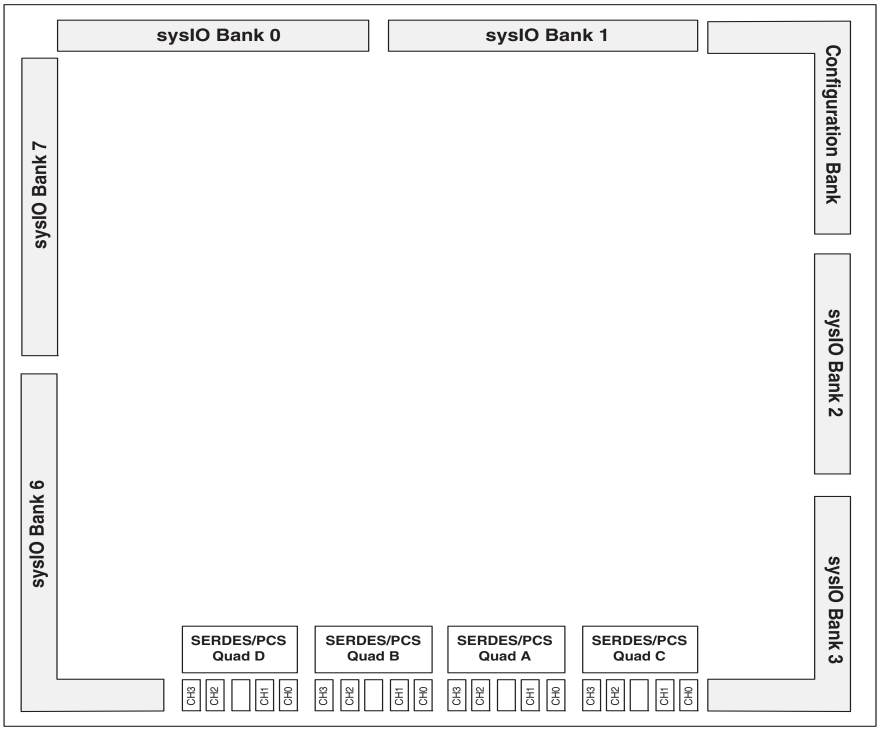


Table 2-13. LatticeECP3 SERDES Standard Support

Standard	Data Rate (Mbps)	Number of General/Link Width	Encoding Style
PCI Express 1.1	2500	x1, x2, x4	8b10b
Gigabit Ethernet	1250, 2500	x1	8b10b
SGMII	1250	x1	8b10b
XAUI	3125	x4	8b10b
Serial RapidIO Type I, Serial RapidIO Type II, Serial RapidIO Type III	1250, 2500, 3125	x1, x4	8b10b
CPRI-1, CPRI-2, CPRI-3, CPRI-4	614.4, 1228.8, 2457.6, 3072.0	x1	8b10b
SD-SDI (259M, 344M)	143[1], 177[1], 270, 360, 540	x1	NRZI/Scrambled
HD-SDI (292M)	1483.5, 1485	x1	NRZI/Scrambled
3G-SDI (424M)	2967, 2970	x1	NRZI/Scrambled
SONET-STS-3[2]	155.52	x1	N/A
SONET-STS-12[2]	622.08	x1	N/A
SONET-STS-48[2]	2488	x1	N/A

1. For slower rates, the SERDES are bypassed and CML signals are directly connected to the FPGA routing.
2. The SONET protocol is supported in 8-bit SERDES mode. See TN1176 Lattice ECP3 SERDES/PCS Usage Guide for more information.

Absolute Maximum Ratings[1, 2, 3]

Supply Voltage V_{CC} . . . . –0.5 V to 1.32 V

Supply Voltage V_{CCAUX} . . . . –0.5 V to 3.75 V

Supply Voltage V_{CCJ} . . . . –0.5 V to 3.75 V

Output Supply Voltage V_{CCIO} . . . . –0.5 V to 3.75 V

Input or I/O Tristate Voltage Applied[4]. . . –0.5 V to 3.75 V

Storage Temperature (Ambient) . . . .–65 V to 150 °C

Junction Temperature (T_J) . . . .+125 °C

1. Stress above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.
2. Compliance with the Lattice Thermal Management document is required.
3. All voltages referenced to GND.
4. Overshoot and undershoot of –2 V to (V_{IHMAX} + 2) volts is permitted for a duration of <20 ns.

Recommended Operating Conditions[1]

Symbol	Parameter	Min.	Max.	Units
V_{CC}[2]	Core Supply Voltage	1.14	1.26	V
V_{CCAUX}[2, 4]	Auxiliary Supply Voltage, Terminating Resistor Switching Power Supply (SERDES)	3.135	3.465	V
V_{CCPLL}	PLL Supply Voltage	3.135	3.465	V
V_{CCIO}[2, 3]	I/O Driver Supply Voltage	1.14	3.465	V
V_{CCJ}[2]	Supply Voltage for IEEE 1149.1 Test Access Port	1.14	3.465	V
V_{REF1} and V_{REF2}	Input Reference Voltage	0.5	1.7	V
V_{TT}[5]	Termination Voltage	0.5	1.3125	V
t_{JCOM}	Junction Temperature, Commercial Operation	0	85	°C
t_{JIND}	Junction Temperature, Industrial Operation	-40	100	°C
SERDES External Power Supply[6]				
V_{CCIB}	Input Buffer Power Supply (1.2 V)	1.14	1.26	V
	Input Buffer Power Supply (1.5 V)	1.425	1.575	V
V_{CCOB}	Output Buffer Power Supply (1.2 V)	1.14	1.26	V
	Output Buffer Power Supply (1.5 V)	1.425	1.575	V
V_{CCA}	Transmit, Receive, PLL and Reference Clock Buffer Power Supply	1.14	1.26	V

1. For correct operation, all supplies except V_{REF} and V_{TT} must be held in their valid operation range. This is true independent of feature usage.
2. If V_{CCIO} or V_{CCJ} is set to 1.2 V, they must be connected to the same power supply as $V_{CC.}$ If V_{CCIO} or V_{CCJ} is set to 3.3 V, they must be connected to the same power supply as V_{CCAUX}.
3. See recommended voltages by I/O standard in subsequent table.
4. V_{CCAUX} ramp rate must not exceed 30 mV/µs during power-up when transitioning between 0 V and 3.3 V.
5. If not used, V_{TT} should be left floating.
6. See TN1176, LatticeECP3 SERDES/PCS Usage Guide for information on board considerations for SERDES power supplies.

MLVDS25

The LatticeECP3 devices support the differential MLVDS standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The MLVDS input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3-5 is one possible solution for MLVDS standard implementation. Resistor values in Figure 3-5 are industry standard values for 1% resistors.

Figure 3-5. MLVDS25 (Multipoint Low Voltage Differential Signaling)

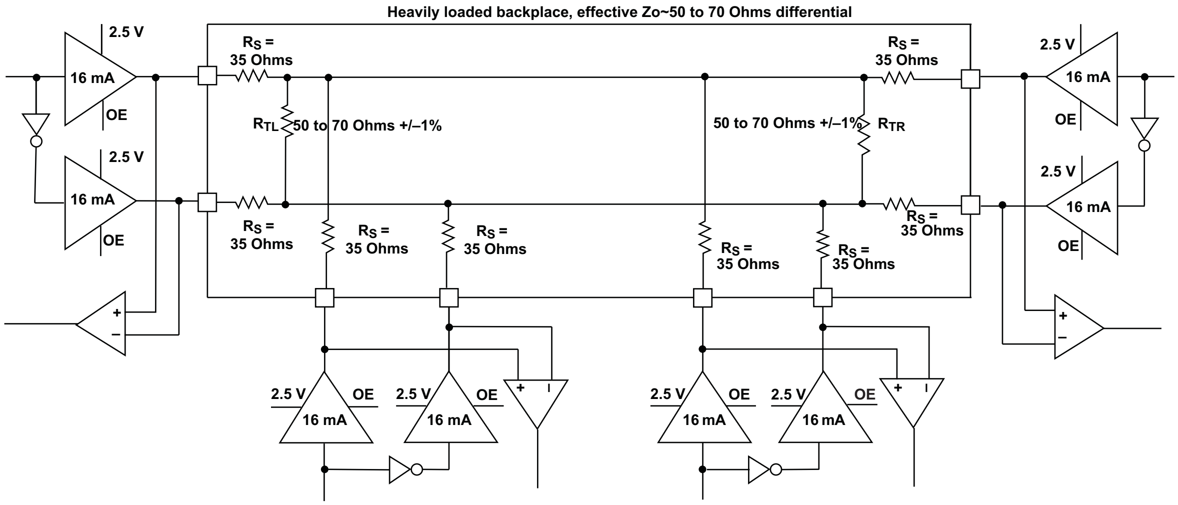


Table 3-5. MLVDS25 DC Conditions[1]

Parameter	Description	Typical		Units
		Zo=50Ω	Zo=70Ω	
V_{CCIO}	Output Driver Supply (+/–5%)	2.50	2.50	V
Z_{OUT}	Driver Impedance	10.00	10.00	Ω
R_S	Driver Series Resistor (+/–1%)	35.00	35.00	Ω
R_{TL}	Driver Parallel Resistor (+/–1%)	50.00	70.00	Ω
R_{TR}	Receiver Termination (+/–1%)	50.00	70.00	Ω
V_{OH}	Output High Voltage	1.52	1.60	V
V_{OL}	Output Low Voltage	0.98	0.90	V
V_{OD}	Output Differential Voltage	0.54	0.70	V
V_{CM}	Output Common Mode Voltage	1.25	1.25	V
I_{DC}	DC Output Current	21.74	20.00	mA

1. For input buffer, see LVDS table.

DLL Timing

Over Recommended Operating Conditions

Parameter	Description	Condition	Min.	Typ.	Max.	Units
f_{REF}	Input reference clock frequency (on-chip or off-chip)		133	—	500	MHz
f_{FB}	Feedback clock frequency (on-chip or off-chip)		133	—	500	MHz
f_{CLKOP}[1]	Output clock frequency, CLKOP		133	—	500	MHz
f_{CLKOS}[2]	Output clock frequency, CLKOS		33.3	—	500	MHz
t_{PJIT}	Output clock period jitter (clean input)			—	200	ps p-p
t_{DUTY}	Output clock duty cycle (at 50% levels, 50% duty cycle input clock, 50% duty cycle circuit turned off, time reference delay mode)	Edge Clock	40		60	%
		Primary Clock	30		70	%
$t_{DUTYTRD}$	Output clock duty cycle (at 50% levels, arbitrary duty cycle input clock, 50% duty cycle circuit enabled, time reference delay mode)	Primary Clock < 250 MHz	45		55	%
		Primary Clock ≥ 250 MHz	30		70	%
		Edge Clock	45		55	%
$t_{DUTYCIR}$	Output clock duty cycle (at 50% levels, arbitrary duty cycle input clock, 50% duty cycle circuit enabled, clock injection removal mode) with DLL cascading	Primary Clock < 250 MHz	40		60	%
		Primary Clock ≥ 250 MHz	30		70	%
		Edge Clock	45		55	%
t_{SKEW}[3]	Output clock to clock skew between two outputs with the same phase setting		—	—	100	ps
t_{PHASE}	Phase error measured at device pads between off-chip reference clock and feedback clocks		—	—	+/-400	ps
t_{PWH}	Input clock minimum pulse width high (at 80% level)		550	—	—	ps
t_{PWL}	Input clock minimum pulse width low (at 20% level)		550	—	—	ps
t_{INSTB}	Input clock period jitter		—	—	500	ps
t_{LOCK}	DLL lock time		8	—	8200	cycles
t_{RSWD}	Digital reset minimum pulse width (at 80% level)		3	—	—	ns
t_{DEL}	Delay step size		27	45	70	ps
t_{RANGE1}	Max. delay setting for single delay block (64 taps)		1.9	3.1	4.4	ns
t_{RANGE4}	Max. delay setting for four chained delay blocks		7.6	12.4	17.6	ns

1. CLKOP runs at the same frequency as the input clock.
2. CLKOS minimum frequency is obtained with divide by 4.
3. This is intended to be a "path-matching" design guideline and is not a measurable specification.

SERDES High-Speed Data Transmitter[1]

Table 3-6. Serial Output Timing and Levels

Symbol	Description	Frequency	Min.	Typ.	Max.	Units
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}1.44}$	Differential swing (1.44 V setting)[1, 2]	0.15 to 3.125 Gbps	1150	1440	1730	mV, p-p
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}1.35}$	Differential swing (1.35 V setting)[1, 2]	0.15 to 3.125 Gbps	1080	1350	1620	mV, p-p
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}1.26}$	Differential swing (1.26 V setting)[1, 2]	0.15 to 3.125 Gbps	1000	1260	1510	mV, p-p
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}1.13}$	Differential swing (1.13 V setting)[1, 2]	0.15 to 3.125 Gbps	840	1130	1420	mV, p-p
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}1.04}$	Differential swing (1.04 V setting)[1, 2]	0.15 to 3.125 Gbps	780	1040	1300	mV, p-p
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}0.92}$	Differential swing (0.92 V setting)[1, 2]	0.15 to 3.125 Gbps	690	920	1150	mV, p-p
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}0.87}$	Differential swing (0.87 V setting)[1, 2]	0.15 to 3.125 Gbps	650	870	1090	mV, p-p
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}0.78}$	Differential swing (0.78 V setting)[1, 2]	0.15 to 3.125 Gbps	585	780	975	mV, p-p
$V_{TX\text{-}DIFF\text{-}P\text{-}P\text{-}0.64}$	Differential swing (0.64 V setting)[1, 2]	0.15 to 3.125 Gbps	480	640	800	mV, p-p
V_{OCM}	Output common mode voltage	—	V_{CCOB} –0.75	V_{CCOB} –0.60	V_{CCOB} –0.45	V
$T_{TX\text{-}R}$	Rise time (20% to 80%)	—	145	185	265	ps
$T_{TX\text{-}F}$	Fall time (80% to 20%)	—	145	185	265	ps
$Z_{TX\text{-}OI\text{-}SE}$	Output Impedance 50/75/HiZ Ohms (single ended)	—	–20%	50/75/ Hi Z	+20%	Ohms
$R_{LTX\text{-}RL}$	Return loss (with package)	—	10			dB
$T_{TX\text{-}INTRASKEW}$	Lane-to-lane TX skew within a SERDES quad block (intra-quad)	—	—	—	200	ps
$T_{TX\text{-}INTERSKEW}$[3]	Lane-to-lane skew between SERDES quad blocks (inter-quad)	—	—	—	1UI +200	ps

1. All measurements are with 50 Ohm impedance.
2. See TN1176, LatticeECP3 SERDES/PCS Usage Guide for actual binary settings and the min-max range.
3. Inter-quad skew is between all SERDES channels on the device and requires the use of a low skew internal reference clock.

Table 3-7. Channel Output Jitter

Description	Frequency	Min.	Typ.	Max.	Units
Deterministic	3.125 Gbps	—	—	0.17	UI, p-p
Random	3.125 Gbps	—	—	0.25	UI, p-p
Total	3.125 Gbps	—	—	0.35	UI, p-p
Deterministic	2.5 Gbps	—	—	0.17	UI, p-p
Random	2.5 Gbps	—	—	0.20	UI, p-p
Total	2.5 Gbps	—	—	0.35	UI, p-p
Deterministic	1.25 Gbps	—	—	0.10	UI, p-p
Random	1.25 Gbps	—	—	0.22	UI, p-p
Total	1.25 Gbps	—	—	0.24	UI, p-p
Deterministic	622 Mbps	—	—	0.10	UI, p-p
Random	622 Mbps	—	—	0.20	UI, p-p
Total	622 Mbps	—	—	0.24	UI, p-p
Deterministic	250 Mbps	—	—	0.10	UI, p-p
Random	250 Mbps	—	—	0.18	UI, p-p
Total	250 Mbps	—	—	0.24	UI, p-p
Deterministic	150 Mbps	—	—	0.10	UI, p-p
Random	150 Mbps	—	—	0.18	UI, p-p
Total	150 Mbps	—	—	0.24	UI, p-p

Note: Values are measured with PRBS 2^7-1, all channels operating, FPGA logic active, I/Os around SERDES pins quiet, reference clock @ 10X mode.

SERDES External Reference Clock

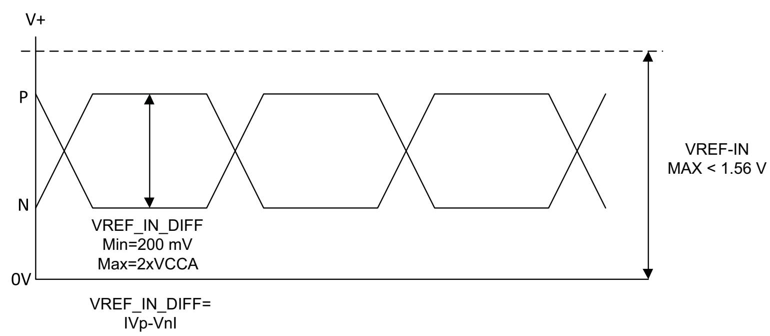
The external reference clock selection and its interface are a critical part of system applications for this product. Table 3-12 specifies reference clock requirements, over the full range of operating conditions.

Table 3-12. External Reference Clock Specification (refclkp/refclkn)

Symbol	Description	Min.	Typ.	Max.	Units
F_{REF}	Frequency range	15	—	320	MHz
$F_{REF-PPM}$	Frequency tolerance[1]	–1000	—	1000	ppm
$V_{REF-IN-SE}$	Input swing, single-ended clock[2]	200	—	V_{CCA}	mV, p-p
$V_{REF-IN-DIFF}$	Input swing, differential clock	200	—	2*V_{CCA}	mV, p-p differential
V_{REF-IN}	Input levels	0	—	V_{CCA} + 0.3	V
D_{REF}	Duty cycle[3]	40	—	60	%
T_{REF-R}	Rise time (20% to 80%)	200	500	1000	ps
T_{REF-F}	Fall time (80% to 20%)	200	500	1000	ps
$Z_{REF-IN-TERM-DIFF}$	Differential input termination	–20%	100/2K	+20%	Ohms
$C_{REF-IN-CAP}$	Input capacitance	—	—	7	pF

1. Depending on the application, the PLL_LOL_SET and CDR_LOL_SET control registers may be adjusted for other tolerance values as described in TN1176, LatticeECP3 SERDES/PCS Usage Guide.
2. The signal swing for a single-ended input clock must be as large as the p-p differential swing of a differential input clock to get the same gain at the input receiver. Lower swings for the clock may be possible, but will tend to increase jitter.
3. Measured at 50% amplitude.

Figure 3-13. SERDES External Reference Clock Waveforms



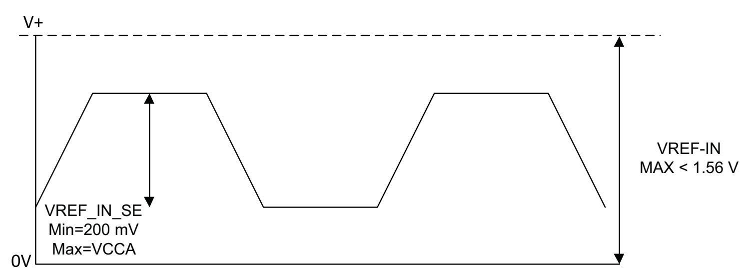


Figure 3-14. Jitter Transfer – 3.125 Gbps

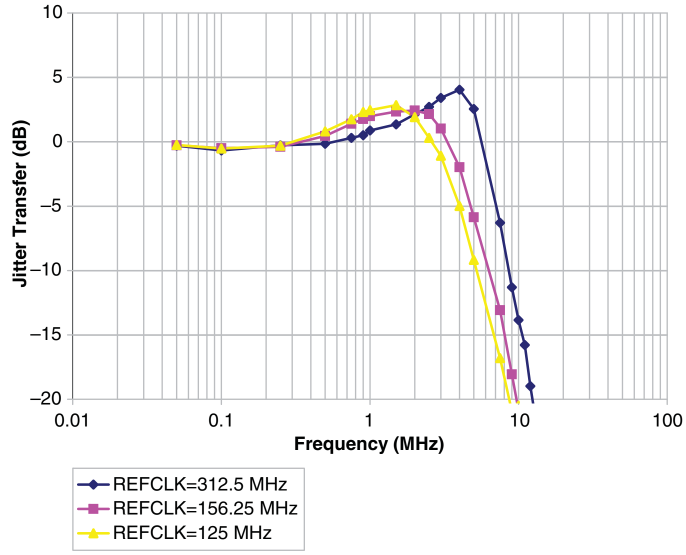
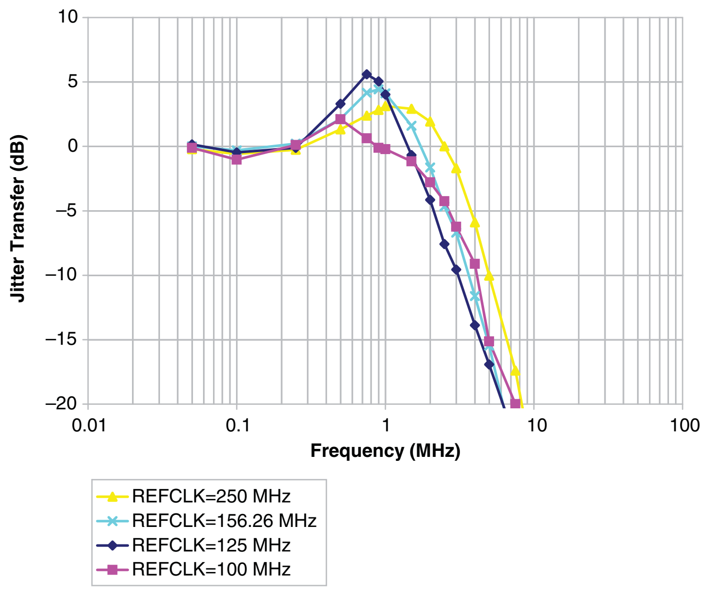


Figure 3-15. Jitter Transfer – 2.5 Gbps



XAUI/Serial Rapid I/O Type 3/CPRI LV E.30 Electrical and Timing Characteristics

AC and DC Characteristics

Table 3-13. Transmit

Over Recommended Operating Conditions

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
T_{RF}	Differential rise/fall time	20%-80%	—	80	—	ps
$Z_{TX\_DIFF\_DC}$	Differential impedance		80	100	120	Ohms
J_{TX_DDJ}[2, 3, 4]	Output data deterministic jitter		—	—	0.17	UI
J_{TX_TJ}[1, 2, 3, 4]	Total output data jitter		—	—	0.35	UI

1. Total jitter includes both deterministic jitter and random jitter.
2. Jitter values are measured with each CML output AC coupled into a 50-Ohm impedance (100-Ohm differential impedance).
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
4. Values are measured at 2.5 Gbps.

Table 3-14. Receive and Jitter Tolerance

Over Recommended Operating Conditions

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
RL_{RX_DIFF}	Differential return loss	From 100 MHz to 3.125 GHz	10	—	—	dB
RL_{RX_CM}	Common mode return loss	From 100 MHz to 3.125 GHz	6	—	—	dB
Z_{RX_DIFF}	Differential termination resistance		80	100	120	Ohms
J_{RX_DJ}[1, 2, 3]	Deterministic jitter tolerance (peak-to-peak)		—	—	0.37	UI
J_{RX_RJ}[1, 2, 3]	Random jitter tolerance (peak-to-peak)		—	—	0.18	UI
J_{RX_SJ}[1, 2, 3]	Sinusoidal jitter tolerance (peak-to-peak)		—	—	0.10	UI
J_{RX_TJ}[1, 2, 3]	Total jitter tolerance (peak-to-peak)		—	—	0.65	UI
T_{RX_EYE}	Receiver eye opening		0.35	—	—	UI

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter. The sinusoidal jitter tolerance mask is shown in Figure 3-18.
2. Jitter values are measured with each high-speed input AC coupled into a 50-Ohm impedance.
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
4. Jitter tolerance parameters are characterized when Full Rx Equalization is enabled.
5. Values are measured at 2.5 Gbps.

Figure 3-28. Master SPI Configuration Waveforms

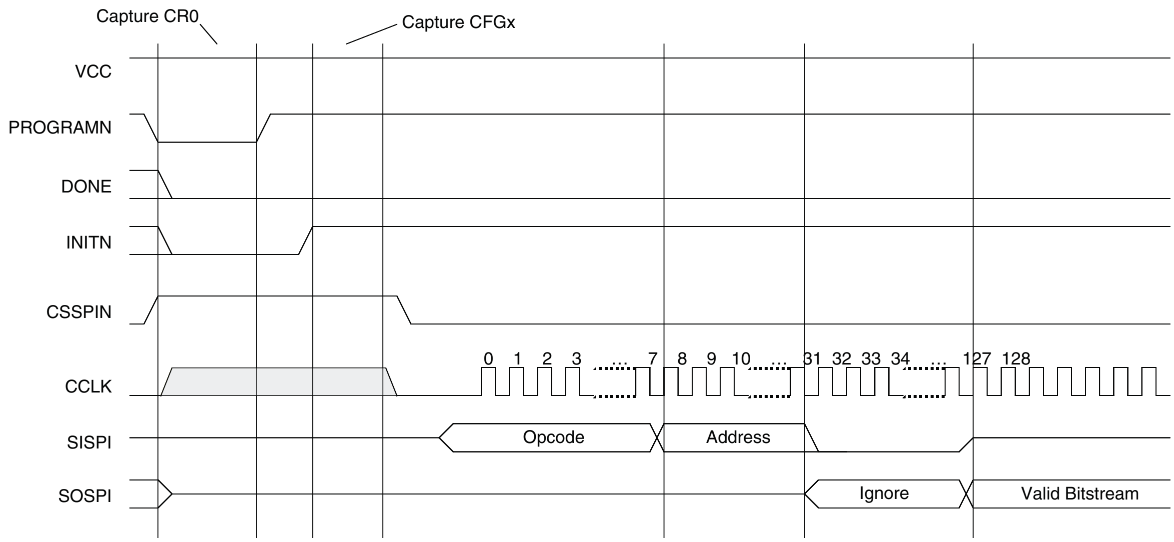
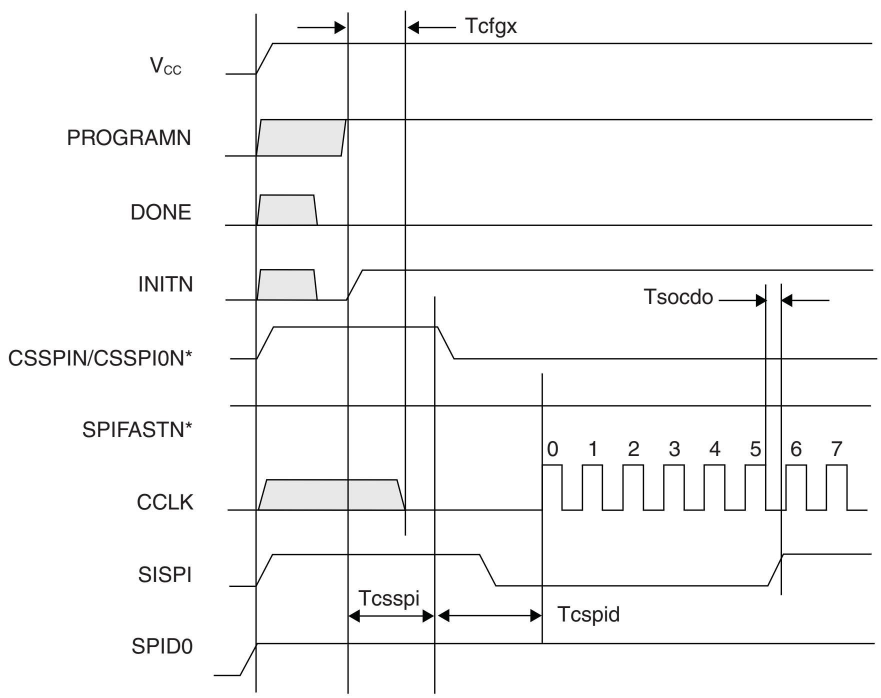


Figure 3-29. Master SPI POR Waveforms



Signal Descriptions (Cont.)

Signal Name	I/O	Description
[LOC]DQS[num]	I/O	DQ input/output pads: T (top), R (right), B (bottom), L (left), DQS, num = ball function number.
[LOC]DQ[num]	I/O	DQ input/output pads: T (top), R (right), B (bottom), L (left), DQ, associated DQS number.
Test and Programming (Dedicated Pins)		
TMS	I	Test Mode Select input, used to control the 1149.1 state machine. Pull-up is enabled during configuration.
TCK	I	Test Clock input pin, used to clock the 1149.1 state machine. No pull-up enabled.
TDI	I	Test Data in pin. Used to load data into device using 1149.1 state machine. After power-up, this TAP port can be activated for configuration by sending appropriate command. (Note: once a configuration port is selected it is locked. Another configuration port cannot be selected until the power-up sequence). Pull-up is enabled during configuration.
TDO	O	Output pin. Test Data Out pin used to shift data out of a device using 1149.1.
VCCJ	—	Power supply pin for JTAG Test Access Port.
Configuration Pads (Used During sysCONFIG)		
CFG[2:0]	I	Mode pins used to specify configuration mode values latched on rising edge of INITN. During configuration, a pull-up is enabled. These are dedicated pins.
INITN	I/O	Open Drain pin. Indicates the FPGA is ready to be configured. During configuration, a pull-up is enabled. It is a dedicated pin.
PROGRAMN	I	Initiates configuration sequence when asserted low. This pin always has an active pull-up. It is a dedicated pin.
DONE	I/O	Open Drain pin. Indicates that the configuration sequence is complete, and the startup sequence is in progress. It is a dedicated pin.
CCLK	I	Input Configuration Clock for configuring an FPGA in Slave SPI, Serial, and CPU modes. It is a dedicated pin.
MCLK	I/O	Output Configuration Clock for configuring an FPGA in SPI, SPIm, and Master configuration modes.
BUSY/SISPI	O	Parallel configuration mode busy indicator. SPI/SPIm mode data output.
CSN/SN/OEN	I/O	Parallel configuration mode active-low chip select. Slave SPI chip select. Parallel burst Flash output enable.
CS1N/HOLDN/RDY	I	Parallel configuration mode active-low chip select. Slave SPI hold input.
WRITEN	I	Write enable for parallel configuration modes.
DOUT/CSON/CSSPI1N	O	Serial data output. Chip select output. SPI/SPIm mode chip select.
D[0]/SPIFASTN	I/O	sysCONFIG Port Data I/O for Parallel mode. Open drain during configuration.
		sysCONFIG Port Data I/O for SPI or SPIm. When using the SPI or SPIm mode, this pin should either be tied high or low, must not be left floating. Open drain during configuration.
D1	I/O	Parallel configuration I/O. Open drain during configuration.
D2	I/O	Parallel configuration I/O. Open drain during configuration.
D3/SI	I/O	Parallel configuration I/O. Slave SPI data input. Open drain during configuration.
D4/SO	I/O	Parallel configuration I/O. Slave SPI data output. Open drain during configuration.
D5	I/O	Parallel configuration I/O. Open drain during configuration.
D6/SPID1	I/O	Parallel configuration I/O. SPI/SPIm data input. Open drain during configuration.

Pin Information Summary

Pin Information Summary		ECP3-17EA			ECP3-35EA			ECP3-70EA		
Pin Type		256 ftBGA	328 csBGA	484 fpBGA	256 ftBGA	484 fpBGA	672 fpBGA	484 fpBGA	672 fpBGA	1156 fpBGA
General Purpose Inputs/Outputs per Bank	Bank 0	26	20	36	26	42	48	42	60	86
	Bank 1	14	10	24	14	36	36	36	48	78
	Bank 2	6	7	12	6	24	24	24	34	36
	Bank 3	18	12	44	16	54	59	54	59	86
	Bank 6	20	11	44	18	63	61	63	67	86
	Bank 7	19	26	32	19	36	42	36	48	54
	Bank 8	24	24	24	24	24	24	24	24	24
General Purpose Inputs per Bank	Bank 0	0	0	0	0	0	0	0	0	0
	Bank 1	0	0	0	0	0	0	0	0	0
	Bank 2	2	2	2	2	4	4	4	8	8
	Bank 3	0	0	0	2	4	4	4	12	12
	Bank 6	0	0	0	2	4	4	4	12	12
	Bank 7	4	4	4	4	4	4	4	8	8
	Bank 8	0	0	0	0	0	0	0	0	0
General Purpose Outputs per Bank	Bank 0	0	0	0	0	0	0	0	0	0
	Bank 1	0	0	0	0	0	0	0	0	0
	Bank 2	0	0	0	0	0	0	0	0	0
	Bank 3	0	0	0	0	0	0	0	0	0
	Bank 6	0	0	0	0	0	0	0	0	0
	Bank 7	0	0	0	0	0	0	0	0	0
	Bank 8	0	0	0	0	0	0	0	0	0
Total Single-Ended User I/O		133	116	222	133	295	310	295	380	490
VCC		6	16	16	6	16	32	16	32	32
VCCAUX		4	5	8	4	8	12	8	12	16
VTT		4	7	4	4	4	4	4	4	8
VCCA		4	6	4	4	4	8	4	8	16
VCCPLL		2	2	4	2	4	4	4	4	4
VCCIO	Bank 0	2	3	2	2	2	4	2	4	4
	Bank 1	2	3	2	2	2	4	2	4	4
	Bank 2	2	2	2	2	2	4	2	4	4
	Bank 3	2	3	2	2	2	4	2	4	4
	Bank 6	2	3	2	2	2	4	2	4	4
	Bank 7	2	3	2	2	2	4	2	4	4
	Bank 8	1	2	2	1	2	2	2	2	2
VCCJ		1	1	1	1	1	1	1	1	1
TAP		4	4	4	4	4	4	4	4	4
GND, GNDIO		51	126	98	51	98	139	98	139	233
NC		0	0	73	0	0	96	0	0	238
Reserved[1]		0	0	2	0	2	2	2	2	2
SERDES		26	18	26	26	26	26	26	52	78
Miscellaneous Pins		8	8	8	8	8	8	8	8	8
Total Bonded Pins		256	328	484	256	484	672	484	672	1156

Pin Information Summary (Cont.)

Pin Information Summary		ECP3-95EA			ECP3-150EA	
Pin Type		484 fpBGA	672 fpBGA	1156 fpBGA	672 fpBGA	1156 fpBGA
Emulated Differential I/O per Bank	Bank 0	21	30	43	30	47
	Bank 1	18	24	39	24	43
	Bank 2	8	12	13	12	18
	Bank 3	20	23	33	23	37
	Bank 6	22	25	33	25	37
	Bank 7	11	16	18	16	24
	Bank 8	12	12	12	12	12
Highspeed Differential I/O per Bank	Bank 0	0	0	0	0	0
	Bank 1	0	0	0	0	0
	Bank 2	6	9	9	9	15
	Bank 3	9	12	16	12	21
	Bank 6	11	14	16	14	21
	Bank 7	9	12	13	12	18
	Bank 8	0	0	0	0	0
Total Single Ended/ Total Differential I/O per Bank	Bank 0	42/21	60/30	86/43	60/30	94/47
	Bank 1	36/18	48/24	78/39	48/24	86/43
	Bank 2	28/14	42/21	44/22	42/21	66/33
	Bank 3	58/29	71/35	98/49	71/35	116/58
	Bank 6	67/33	78/39	98/49	78/39	116/58
	Bank 7	40/20	56/28	62/31	56/28	84/42
	Bank 8	24/12	24/12	24/12	24/12	24/12
DDR Groups Bonded per Bank	Bank 0	3	5	7	5	7
	Bank 1	3	4	7	4	7
	Bank 2	2	3	3	3	4
	Bank 3	3	4	5	4	7
	Bank 6	4	4	5	4	7
	Bank 7	3	4	4	4	6
	Configuration Bank8	0	0	0	0	0
SERDES Quads		1	2	3	2	4

1.These pins must remain floating on the board.

LatticeECP3 Family Data Sheet
Ordering Information

April 2014 **Data Sheet DS1021**

LatticeECP3 Part Number Description

LFE3 – XXX XX – X X XXXXXX X

Device Family
ECP3 (LatticeECP3 FPGA + SERDES)

Logic Capacity
17 = 17K LUTs
35 = 33K LUTs
70 = 67K LUTs
95 = 92K LUTs
150 = 149K LUTs

Supply Voltage
EA = 1.2 V

Speed
6 = Slowest
7
8 = Fastest for LatticeECP3-17EA

Grade
C = Commercial
I = Industrial

Package
FTN256 = 256-ball Lead-Free ftBGA
FN484 = 484-ball Lead-Free fpBGA
FN672 = 672-ball Lead-Free fpBGA
FN1156 = 1156-ball Lead-Free fpBGA
MG328 = 328-ball Green csBGA[1]

Power
Blank = Standard Power
L = Low Power

1. Green = Halogen free and lead free.

Ordering Information

LatticeECP3 devices have top-side markings, for commercial and industrial grades, as shown below:

Commercial	Industrial
LATTICE LFE3-95EA 7FN672C Datecode	LATTICE LFE3-95EA 7FN672I Datecode

Note: See PCN 05A-12 for information regarding a change to the top-side mark logo.

Date	Version	Section	Change Summary
			Updated Frequency to 150 Mbps in Table 3-11 Periodic Receiver Jitter Tolerance Specification
December 2010	01.7EA	Multiple	Data sheet made final. Removed “preliminary” headings.
			Removed data for 70E and 95E devices. A separate data sheet is available for these specific devices.
			Updated for Lattice Diamond design software.
		Introduction	Corrected number of user I/Os
		Architecture	Corrected the package type in Table 2-14 Available SERDES Quad per LatticeECP3 Devices.
			Updated description of General Purpose PLL
			Added additional information in the Flexible Quad SERDES Architecture section.
			Added footnotes and corrected the information in Table 2-16 Selectable master Clock (MCCLK) Frequencies During Configuration (Nominal).
			Updated Figure 2-16, Per Region Secondary Clock Selection.
			Updated description for On-Chip Programmable Termination.
			Added information about number of rows of DSP slices.
			Updated footnote 2 for Table 2-12, On-Chip Termination Options for Input Modes.
			Updated information for sysIO buffer pairs.
			Corrected minimum number of General Purpose PLLs (was 4, now 2).
		DC and Switching Characteristics	Regenerated sysCONFIG Port Timing figure.
			Added t_W (clock pulse width) in External Switching Characteristics table.
			Corrected units, revised and added data, and corrected footnote 1 in External Switching Characteristics table.
			Added Jitter Transfer figures in SERDES External Reference Clock section.
			Corrected capacitance information in the DC Electrical Characteristics table.
			Corrected data in the Register-to-Register Performance table.
			Corrected GDDR Parameter name HOGDDR.
			Corrected RSDS25 -7 data in Family Timing Adders table.
			Added footnotes 10-12 to DDR data information in the External Switching Characteristics table.
			Corrected titles for Figures 3-7 (DDR/DDR2/DDR3 Parameters) and 3-8 (Generic DDR/DDRX2 Parameters).
			Updated titles for Figures 3-5 (MLVDS25 (Multipoint Low Voltage Differential Signaling)) and 3-6 (Generic DDRX1/DDRX2 (With Clock and Data Edges Aligned)).
			Updated Supply Current table.
			Added GDDR interface information to the External Switching and Characteristics table.
			Added footnote to sysIO Recommended Operating Conditions table.
			Added footnote to LVDS25 table.
			Corrected DDR section footnotes and references.
			Corrected Hot Socketing support from “top and bottom banks” to “top and bottom I/O pins”.
		Pinout Information	Updated description for VTTx.